Unit: mm

TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type

SSM3K125TU

High-Speed Switching Applications

• 4.0 V drive

• Low ON-resistance: $R_{on} = 181 \text{ m}\Omega \text{ (max) (@V_{GS} = 4 V)}$

 $R_{on} = 148 \text{ m}\Omega \text{ (max) (@V_{GS} = 10 V)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-Source voltage		V_{DS}	60	V	
Gate-Source voltage		V _{GSS}	± 20	V	
Drain current	DC	I _D	1.8	Α	
	Pulse	I _{DP}	3.6		
Drain power dissipation		P _D (Note 1)	800	mW	
		P _D (Note 2)	500		
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	−55~150	°C	

Note 1: Mounted on a ceramic board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 0.8 \text{ t}, \text{ Cu Pad: } 645 \text{ mm}^2)$

Note 2: Mounted on a FR4 board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu Pad: } 645 \text{ mm}^2)$

2.1±0.1 1.7±0.1 1.7±0.0 1: Gate 2: Source UFM 3: Drain

2-2U1A

Weight: 6.6 mg (typ.)

TOSHIBA

Electrical Characteristics (Ta = 25°C)

Characte	eristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain-Source breakdown voltage	V (BR) DSS	$I_D = 1 \text{ mA}, V_{GS} = 0$	60	_	_	V	
	V (BR) DSX	$I_D = 1 \text{ mA}, V_{GS} = -20 \text{ V}$	45	_	_		
Drain cutoff current	t	I _{DSS}	$V_{DS} = 60 \text{ V}, V_{GS} = 0$	_	_	1	μА
Gate leakage curre	ent	I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$	_	_	±1	
Gate threshold volt	age	V _{th}	V _{DS} = 5 V, I _D = 1 mA	1.1	_	2.6	V
Forward transfer a	dmittance	Y _{fs}	$V_{DS} = 5 \text{ V}, I_D = 1.5 \text{ A}$ (Note 3)	4.2	8.3	_	S
Drain-Source ON-resistance	R _{DS} (ON)	$I_D = 1.5 \text{ A}, V_{GS} = 10 \text{ V}$ (Note 3)	_	112	148	mΩ	
		$I_D = 1.0 \text{ A}, V_{GS} = 4.0 \text{ V}$ (Note 3)	_	126	181		
Input capacitance		C _{iss}		_	248	_	
Output capacitance		C _{oss}	$V_{DS} = 30 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	41	_	pF
Reverse transfer ca	apacitance	C _{rss}		_	8.4	_	
Total Gate Charge		Q_g	V - 20 V I - 4 0 A	_	4.1	_	
Gate-Source Charge		Q_{gs}	$V_{DS} = 30 \text{ V}, I_{DS} = 1.8 \text{ A}$	_	3.5	_	nC
Gate-Drain Charge	$V_{GS} = 10 \text{ V}$		_	0.6	_		
Switching time	Turn-on time	t _{on}	V _{DD} = 30 V, I _D = 1 A,	_	8	_	
	Turn-off time	t _{off}	$V_{GS} = 0~4.0 \text{ V}, R_G = 10 \Omega$	_	7	_	ns
Drain-Source forwa	ard voltage	V _{DSF}	$I_D = -1.8 \text{ A}, V_{GS} = 0 \text{ V}$ (Note 3)	_	-0.8	-1.2	V

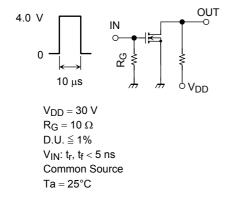
Note 3: Pulse test

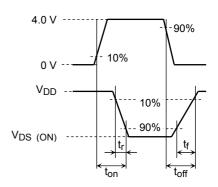
Switching Time Test Circuit

(a) Test Circuit

(b) V_{IN}

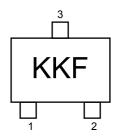
(c) Vout

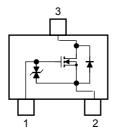




Marking

Equivalent Circuit (top view)





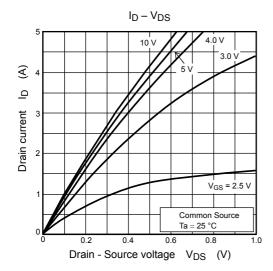
Notice on Usage

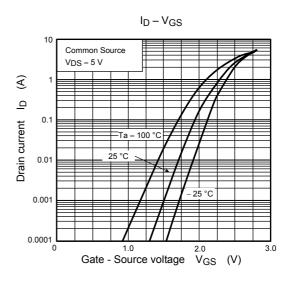
 V_{th} can be expressed as the voltage between gate and source when the low operating current value is I_D = 1 mA for this product. For normal switching operation, V_{GS} (on) requires a higher voltage than V_{th} , and V_{GS} (off) requires a lower voltage than V_{th} . (The relationship can be established as follows: V_{GS} (off) < V_{th} < V_{GS} (on).)

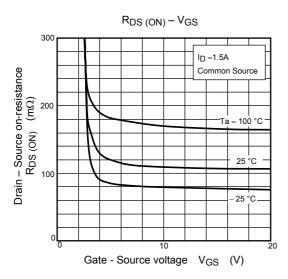
Take this into consideration when using the device.

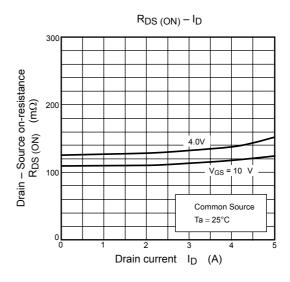
Handling Precaution

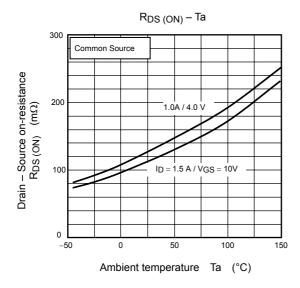
When handling individual devices that are not yet mounted on a circuit board, make sure that the environment is protected against electrostatic discharge. Operators should wear antistatic clothing, and containers and other objects that come into direct contact with devices should be made of antistatic materials.

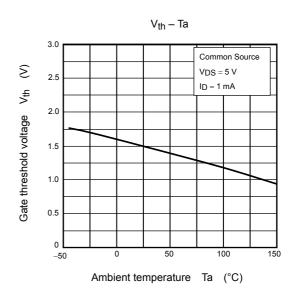


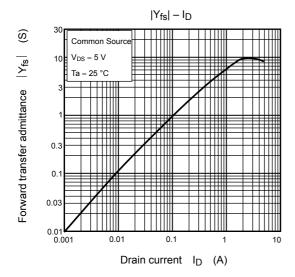


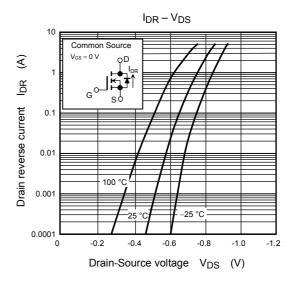


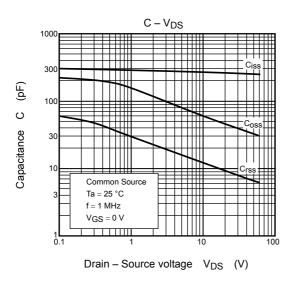


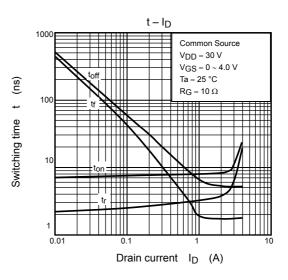


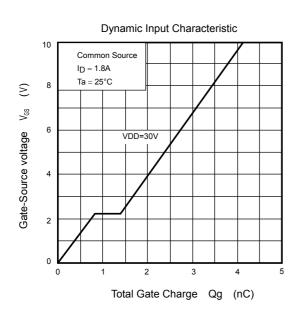




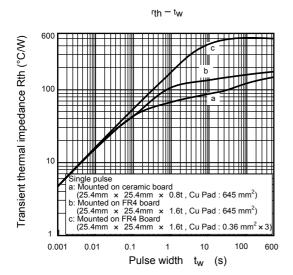


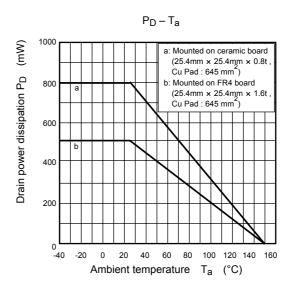






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RESTRICTIONS ON PRODUCT USE

Handbook" etc. 021023_A

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